

Surface Analytical Techniques

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CLARENDON PRESS · OXFORD

1990

CONTENTS

1	Introduction	1
2	Resumé of physical principles	5
2.1	Electron excitation	5
2.2	Photon excitation	11
2.3	Ion excitation	14
2.4	Other techniques	19
2.5	Surface specificity	22
3	Instrumentation	27
3.1	Vacuum conditions	27
3.2	Sources	28
3.3	Analysers	53
3.4	Sample insertion and handling	66
3.5	Depth profiling	70
4	Electron excitation: Auger electron spectroscopy (AES) and scanning Auger microscopy (SAM)	81
4.1	Operation	81
4.2	Spectral features and interpretation	85
4.3	Quantification	97
4.4	Applications	102
5	Electron excitation: electron energy loss spectroscopy (ELS), core electron energy loss spectroscopy (CEELS), and high resolution electron energy loss spectroscopy (HREELS)	125
5.1	Operation	125
5.2	Spectral features and interpretation	126
5.3	Quantification	141
5.4	Applications	144
6	Electron excitation: soft X-ray appearance potential spectroscopy (SXAPS), Auger electron appearance potential spectroscopy (AEAPS), and dis-appearance potential spectroscopy (DAPS)	167
6.1	Operation	167
6.2	Theory and spectral identification	172
6.3	Applications	181

7	Electron excitation: inverse photoemission spectroscopy (IPES)	193
7.1	Operation	193
7.2	Theory and spectral identification	197
7.3	Applications	202
8	Electron excitation: cathodoluminescence spectroscopy (CLS)	210
8.1	Operation	210
8.2	Theory and spectral identification	210
8.3	Applications	212
9	Electron excitation: electron stimulated desorption (ESD) and electron simulated desorption ion angular distribution (ESDIAD)	219
9.1	Operation	219
9.2	Theory and spectral interpretation	223
9.3	Applications	229
10	Photon excitation: X-ray photoelectron spectroscopy (XPS) and X-ray excited Auger electron spectroscopy (XAES)	238
10.1	Operation	238
10.2	Spectral interpretation	258
10.3	Theory	265
10.4	Quantification	274
10.5	The Auger Parameter	278
10.6	Fine structure in Auger spectra studied by XAES	280
10.7	Applications	283
11	Photon excitation: ultra-violet photoelectron spectroscopy (UPS) and synchrotron radiation photoelectron spectroscopy (SRPS)	314
11.1	Operation	314
11.2	Theory and spectral interpretation	318
11.3	Quantification	338
11.4	Applications	340
12	Photon excitation: reflection-absorption infra-red spectroscopy (RAIRS) and surface-enhanced Raman spectroscopy (SERS)	357
12.1	Reflection-absorption infra-red spectroscopy	357
12.1.1	Operation	357
12.1.2	Theory and spectral interpretation	362
12.1.3	Quantification	367

12.1.4	Applications	369
12.2	Surface-enhanced Raman spectroscopy	373
12.2.1	Operation	374
12.2.2	Theory and spectral interpretation	375
12.2.3	Quantification	378
12.2.4	Applications	378
13	Ion excitation: ion-excited Auger electron spectroscopy (IAES) and proton-excited Auger electron spectroscopy (PAES)	386
13.1	Operation	386
13.2	Theory and spectral interpretation	391
13.3	Quantification and applications	401
14	Ion excitation: ion neutralization spectroscopy (INS) and metastable quenching spectroscopy (MQS)	403
14.1	Ion neutralization spectroscopy	403
14.1.1	Operation	403
14.1.2	Theory and data processing	406
14.1.3	Spectral interpretation	410
14.2	Metastable quenching spectroscopy	417
15	Ion excitation: ion beam spectrochemical analysis (IBSCA) and glow discharge optical spectroscopy (GDOS)	423
15.1	Ion beam spectro-chemical analysis	423
15.1.1	Operation	423
15.1.2	Theory and quantification	425
15.1.3	Applications	429
15.2	Glow discharge optical spectroscopy	431
15.2.1	Operation	432
15.2.2	Quantification	435
15.2.3	Applications	439
16	Ion excitation: ion scattering spectroscopy (ISS)	445
16.1	Operation	445
16.2	Theory and spectral interpretation	450
16.3	Quantification	454
16.4	Applications	459
16.5	Surface structural analysis	467
17	Ion excitation: static secondary ion mass spectrometry (SSIMS)	470
17.1	Operation	470
17.2	Spectral identification	480

17.3	Theory	482
17.4	Quantification	504
17.5	Applications	514
18	Ion excitation: secondary neutral mass spectrometry (SNMS) and glow discharge mass spectrometry (GDMS)	528
18.1	Secondary neutral mass spectrometry	528
18.1.1	Operation	528
18.1.2	Theory	545
18.1.3	Spectral interpretation	552
18.1.4	Quantification	554
18.1.5	Applications	559
18.2	Glow discharge mass spectrometry	563
18.2.1	Operation	563
18.2.2	Theory and spectral identification	567
18.2.3	Quantification	567
18.2.4	Applications	572
19	Neutral excitation: fast atom bombardment mass spectrometry (FABMS)	578
19.1	Operation	578
19.2	Theory	580
19.3	Spectral interpretation and quantification	585
19.4	Applications	585
20	High field excitation: inelastic electron tunnelling spectroscopy (IETS)	593
20.1	Operation	593
20.2	Theory	598
20.3	Spectral identification	604
20.4	Quantification	607
20.5	Applications	612
21	High field excitation: atom probe field ion microscopy (APFIM)	620
21.1	Operation	620
21.2	Theory	629
21.3	Spectral interpretation	631
21.4	Quantification	632
21.5	Applications	633

22	High field excitation: scanning tunnelling microscopy and spectroscopy (STM and STS)	648
22.1	Operation	648
22.2	Theory and image interpretation	655
22.3	Quantification	660
22.4	Applications	660
23	Thermal excitation: thermal desorption spectroscopy (TDS)	671
23.1	Operation	671
23.2	Theory and interpretation	673
23.3	Quantification	678
23.4	Applications	681
Index		691